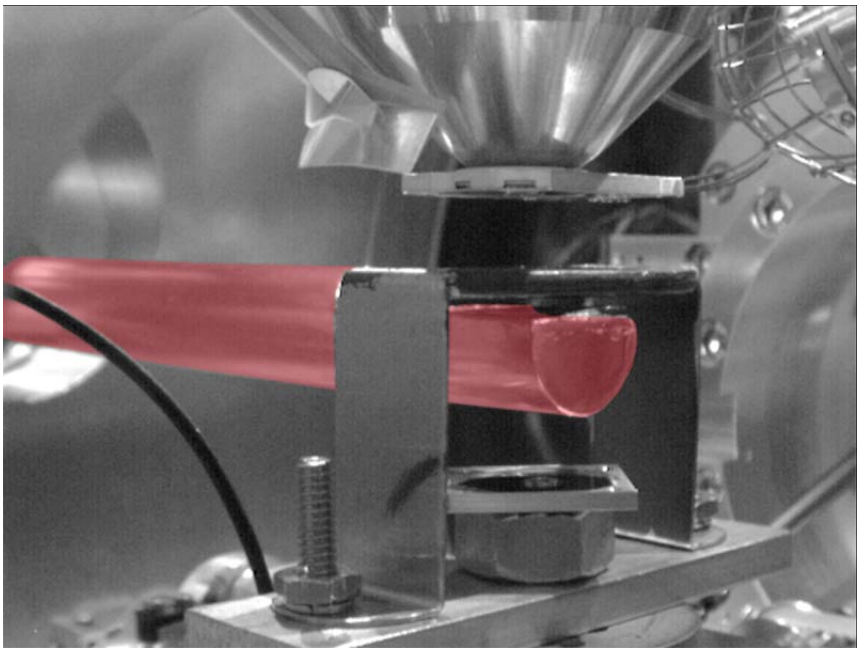
2010 R&D 100 Award Winner

The π Steradian Transmission X-ray Detection System for Nanoscale Analysis in Electron Microscopes and Electron Optical Beam Lines



This product is an ultra high collection efficiency transmission X-ray detection system for use in electron-optical instruments that facilitates nanomaterials characterization. This product provides as much as 500 times improvement in performance over existing, similar commercial technology.